EESTI STANDARD EVS-EN 165000-3:2002



# Film and hybrid integrated circuits - Part 3: Self-audit checklist and report for film and hybrid integrated circuit manufacturers

EESTI STANDARDIKESKUS

## EESTI STANDARDI EESSÕNA

## NATIONAL FOREWORD

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|---|---|
| Käesolev Eesti standard EVS-EN 165000-3:2002 sisaldab Euroopa standardi EN 165000-3:1996 ingliskeelset teksti. | This Estonian standard EVS-EN 165000-3:2002 consists of the English text of the European standard EN 165000-3:1996. |
| Käesolev dokument on jõustatud 18.12.2002 ja selle kohta on avaldatud teade Eesti standardiorganisatsiooni ametlikus väljaandes. | This document is endorsed on 18.12.2002 with the notification being published in the official publication of the Estonian national standardisation organisation. |
| Standard on kättesaadav Eesti standardiorganisatsioonist. | The standard is available from Estonian standardisation organisation. |



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Descriptors: Quality, generic specification, hybrid circuits

English version

# Film and hybrid integrated circuits Part 3: Self-audit checklist and report for film and hybrid integrated circuit manufacturers



This European Standard was approved by CENELEC on 1996-03-05. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

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CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

**Central Secretariat: rue de Stassart 35, B - 1050 Brussels**

## Foreword

This European Standard was prepared by CLC/TC CECC SC 47AX (former CECC/WG 21), Film and hybrid integrated circuits.

The text of the draft was submitted to the Unique Acceptance Procedure and was approved by CENELEC as EN 165000-3 on 1996-03-05.

The following dates were fixed:

- latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 1997-03-01
- latest date by which the national standards conflicting with the EN have to be withdrawn (dow) 1997-03-01

The present standard, EN 165000-3, Film and hybrid integrated circuits - Part 3: Self-audit checklist and report for film and hybrid integrated circuit manufacturers, is intended to be read in conjunction with the other parts of EN 165000, which are:

Part 1: Generic Specification - Capability approval procedure
Part 2: Part 2: Internal visual inspection and special tests
Part 4: Customer information, product assessment level schedules and blank detail specification

This part 3 is primarily intended as a pro-forma for the manufacturer and is not considered *essential* for a customer *in this form*.

Part 4 is considered an essential document for all users; in particular it includes a helpful introductory section which is aimed at potential customers and seeks to explain the underlying philosophy upon which the whole standard is based.

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## 1. SCOPE

This checklist is intended for the use of a hybrid microcircuit manufacturer's internal assessment team. It will provide the hybrid manufacturer and the ONS with ongoing information on process control demonstrating compliance with EN 165000-1. It is not intended to include Quality System requirements.

## 2. DOCUMENT INFORMATION

### 2.1 Introduction

The checklist and subsequent report is for submission to the ONS in support of an application for approval to EN 165000-1 or as demonstration of continuing compliance at intervals not exceeding 1 year. Each section shall be completed or marked not applicable; sections which invoke mandatory process or inspection requirements are shown in ***bold italics***.

It should be noted that it is not the requirement or the intention that each section has to be answered with an affirmative, excepting mandatory requirements. The objective of the report is for the maufacturer to demonstrate that all manufacturing processes are under control by whatever means this is achieved.

Where supporting evidence is included, for example Engineering reports, SPC data etc, it should be appended to the report.

The manufacturer may use his own style of typeface to reproduce this document and produce his report.

The ONS may subsequently validate any part of the submission as a process assessment.

### 2.2 **Related documents.**

| | | |
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| EN 165000-1 | Generic Specification for film and hybrid integrated circuits, capability approval procedure | |
| EN 100114-1 | Quality assessment procedures: Approval of manufacturers and other organisations. | |
| CECC 00114/111 | Quality assessment procedures. Capability approval of an electronic component manufacturing activity. | |
| EN 100012 | Basic specification: | Radiographic inspection of electronic components. |
| EN 100015 | Basic specification: | Protection of electrostatic sensitive devices. |
| CECC 00016 | Basic specification: | Basic requirements for the use of statistical process control (SPC) in the CECC system. |